

Notice of References Cited	Application/Control No. 10/708,679	Applicant(s)/Patent Under Reexamination LU ET AL.	
	Examiner Christopher P. Schwartz	Art Unit 3683	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,265,019 A	11-1993	Harara et al.	701/41
	B	US-6,269,307 B1	07-2001	Shinmura et al.	701/301
	C	US-6,374,162 B1	04-2002	Tanaka et al.	701/1
	D	US-6,405,113 B1	06-2002	Yamawaki et al.	701/41
	E	US-6,415,215 B1	07-2002	Nishizaki et al.	701/70
	F	US-6,588,858 B2	07-2003	Ritz et al.	303/140
	G	US-6,597,975 B1	07-2003	Shinmura et al.	701/48
	H	US-6,612,394 B2	09-2003	Wessman, Bjorn Gosta	180/446
	I	US-2002/0066616 A1	06-2002	Wessman, Bjorn Gosta	180/446
	J	US-2003/0196847 A1	10-2003	Zheng et al.	180/402
	K	US-2003/0010545 A1	01-2003	Takeuchi, Kesatoshi	180/6.28
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.